



Docket No.: H6808.0032/P032
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Shuichi Takeuchi, et al.

Examiner: Kalimah Fernandez

Application No.: 10/750,838

Art Unit: 2881

Filed: January 5, 2004

For: SCANNING ELECTRON MICROSCOPE
AND SAMPLE OBSERVING METHOD
USING IT

AMENDMENT

Commissioner for Patents
MS: Amendment
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

This paper is in response to the Office Action dated October 5, 2004. Please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 11 of this paper.